### SN54LVTH16240, SN74LVTH16240 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS SCBS684-MARCH 1997

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<ul> <li>Members of the Texas Instruments Widebus<sup>™</sup> Family</li> </ul>	SN54LVTH16240 WD PACKAGE SN74LVTH16240 DGG, DGV, OR DL PACKAGE (TOP VIEW)					
<ul> <li>State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low-Static Power Dissipation</li> </ul>	10E 1 48 20E 1Y1 2 47 1A1 1Y2 3 46 1A2					
<ul> <li>Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V<sub>CC</sub>)</li> </ul>	GND					
<ul> <li>Support Unregulated Battery Operation Down to 2.7 V</li> </ul>	V <sub>CC</sub> [] 7   42 [] V <sub>CC</sub> 2Y1 [] 8   41 [] 2A1					
<ul> <li>High-Impedance State During Power Up and Power Down</li> </ul>	2Y2 0 9 40 0 2A2 GND 0 10 39 0 GND					
<ul> <li>Typical V<sub>OLP</sub> (Output Ground Bounce)</li> <li>&lt; 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C</li> </ul>	2Y3   11 38   2A3 2Y4   12 37   2A4					
<ul> <li>ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)</li> </ul>	3Y1 [] 13 36 [] 3A1 3Y2 [] 14 35 [] 3A2 GND [] 15 34 [] GND					
<ul> <li>Latch-Up Performance Exceeds 500 mA Per JESD 17</li> </ul>	3Y3 [] 16 33 [] 3A3 3Y4 [] 17 32 [] 3A4 V <sub>CC</sub> [] 18 31 [] V <sub>CC</sub>					
<ul> <li>Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors</li> </ul>	4Y1 [] 19 30 [] 4A1 4Y2 [] 20 29 [] 4A2					
<ul> <li>Power Off Disables Inputs/Outputs, Permitting Live Insertion</li> </ul>	GND 21 28 GND 4Y3 22 27 4A3 4Y4 23 26 4A4					

- Distributed V<sub>CC</sub> and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

## description

These 16-bit buffers/drivers are designed specifically for low-voltage (3.3-V) V<sub>CC</sub> operation, but with the capability to provide a TTL interface to a 5-V system environment.

The 'LVTH16240 are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. The devices provide inverting outputs and symmetrical active-low output-enable ( $\overline{OE}$ ) inputs.



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## description (continued)

When  $V_{CC}$  is between 0 and 1.5 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54LVTH16240 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74LVTH16240 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

FUNCTION TABLE	
(each 4-bit buffer)	

INP	JTS	OUTPUT							
OE	Α	Y							
L	Н	L							
L	L	Н							
н	Х	Z							

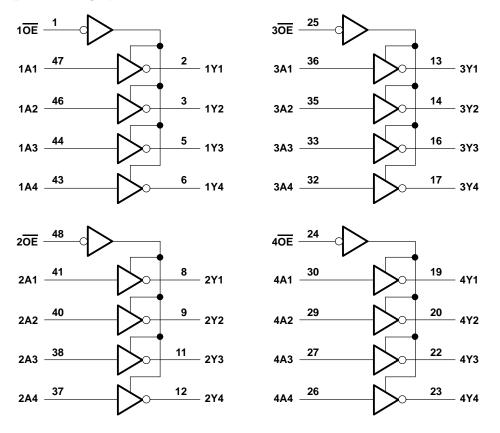
## logic symbol<sup>†</sup>

1 <mark>0E</mark>	1	EN1				
2 <mark>0E</mark>	48	EN2				
3 <mark>0E</mark>	25	EN3				
	24					
4 <mark>0E</mark>		EN4				
1A1	47		1		2	– 1Y1
1A2	46		•	IV	3	- 1Y2
	44				5	
1A3	43	<b> </b>			6	- 1Y3
1A4	41				8	– 1Y4
2A1	40	<b> </b>	1	2 ▽	9	– 2Y1
2A2	38				11	– 2Y2
2A3	37				12	– 2Y3
2A4	36				13	– 2Y4
3A1		-	1	3 🗸	<u> </u>	– 3Y1
3A2	35				14	- 3Y2
3A3	33	<u> </u>			16	- 3Y3
3A4	32	<u> </u>			17	- 3Y4
4A1	30		1	4 ▽	19	- 4Y1
	29			4 \	20	
4A2	27				22	- 4Y2
4A3	26	┣───			23	- 4Y3
4A4						- 4Y4

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



## logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	V
Input voltage range, VI (see Note 1) –0.5 V to 7	V
Voltage range applied to any output in the high or power-off state, V <sub>O</sub> (see Note 1)0.5 V to 7	V
Current into any output in the low state, IO: SN54LVTH16240	۱A
SN74LVTH16240	
Current into any output in the high state, I <sub>O</sub> (see Note 2): SN54LVTH16240	ìΑ
SN74LVTH16240 64 m	
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	ìΑ
Output clamp current, $I_{OK}$ (V <sub>O</sub> < 0)	
Package thermal impedance, $\theta_{JA}$ (see Note 3): DGG package	
DGV package	
DL package	
Storage temperature range, T <sub>stg</sub> 65°C to 150°	Ъ

<sup>+</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .
  - 3. The package thermal impedance is calculated in accordance with JESD 51.



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## recommended operating conditions (see Note 4)

		:					UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		2.7	3.6	2.7	3.6	V
VIH	High-level input voltage	2	M	2		V	
VIL	Low-level input voltage		0.8		0.8	V	
VI	Input voltage	4	5.5		5.5	V	
ЮН	High-level output current	6	-24		-32	mA	
IOL	Low-level output current		nc	48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	00	10		10	ns/V
$\Delta t / \Delta V_{CC}$	Power-up ramp rate		<b>Q</b> 200		200		μs/V
Т <sub>А</sub>	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.



## SN54LVTH16240, SN74LVTH16240 **16-BIT BÚFFERS/DRIVERS** WITH 3-STATE OUTPUTS

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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TERT CON	SN54I	_VTH1624	10	SN74L	VTH162	40	UNIT		
PAr	RAMEIER	TEST CON	MIN	TYP†	т мах	MIN	TYP†	MAX	UNIT		
VIK		V <sub>CC</sub> = 2.7 V,	lj = –18 mA		-1.2				-1.2	V	
		V <sub>CC</sub> = 2.7 V to 3.6 V,	I <sub>OH</sub> = –100 μA	V <sub>CC</sub> -0.2			V <sub>CC</sub> -0.2				
		V <sub>CC</sub> = 2.7 V,	I <sub>OH</sub> =8 mA	2.4			2.4			v	
VOH			I <sub>OH</sub> = -24 mA	2							
		V <sub>CC</sub> = 3 V	I <sub>OH</sub> = -32 mA 2								
			I <sub>OL</sub> = 100 μA			0.2			0.2		
		$V_{CC} = 2.7 V$	I <sub>OL</sub> = 24 mA			0.5			0.5		
N/			I <sub>OL</sub> = 16 mA			0.4			0.4	v	
VOL		N 0.V	I <sub>OL</sub> = 32 mA			0.5			0.5	V	
		V <sub>CC</sub> = 3 V	I <sub>OL</sub> = 48 mA			0.55					
			I <sub>OL</sub> = 64 mA						0.55		
		V <sub>CC</sub> = 0 or 3.6 V,	V <sub>I</sub> = 5.5 V		N.	10			10		
1.	Control inputs	V <sub>CC</sub> = 3.6 V,	$V_{I} = V_{CC} \text{ or } GND$		N	±1			±1		
lj –	Data inputs	V <sub>CC</sub> = 3.6 V	$V_{I} = V_{CC}$		2	1			1	μA	
			V <sub>I</sub> = 0		1	-5			-5		
loff		$V_{CC} = 0$ , $V_{I}$ or $V_{O} = 0$	to 4.5 V	)/,	5	±100	00 ±100		±100	μΑ	
1.a	Data inputa		V <sub>I</sub> = 0.8 V	75			75			A	
l(hold)	Data inputs	V <sub>CC</sub> = 3 V	V <sub>I</sub> = 2 V	<b>2</b> 75			-75			μA	
IOZH		V <sub>CC</sub> = 3.6 V,	V <sub>O</sub> = 3 V			5			5	μΑ	
IOZL		V <sub>CC</sub> = 3.6 V,	V <sub>O</sub> = 0.5 V			-5			-5	μΑ	
IOZPU <sup>‡</sup>		$\frac{V_{CC}}{OE} = 0$ to 1.5 V, V <sub>O</sub> = OE = don't care	= 0.5 V to 3 V,			±100			±100	μA	
I <sub>OZPD</sub> ‡		$\frac{V_{CC}}{OE}$ = 1.5 V to 0, V <sub>O</sub> = OE = don't care	= 0.5 V to 3 V,			±100			±100	μA	
			Outputs high	Outputs high		0.19			0.19		
ICC		$V_{CC} = 3.6 \text{ V}, \text{ I}_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low			5			5	mA	
			Outputs disabled			0.19			0.19		
∆I <sub>CC</sub> § One inp		$V_{CC} = 3 V \text{ to } 3.6 V,$ One input at $V_{CC} - 0.6 Other$ inputs at $V_{CC}$ or				0.2			0.2	mA	
Ci		V <sub>I</sub> = 3 V or 0			4			4		pF	
Co		V <sub>O</sub> = 3 V or 0			9			9		pF	

<sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. <sup>‡</sup> This parameter is warranted but not production tested.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.



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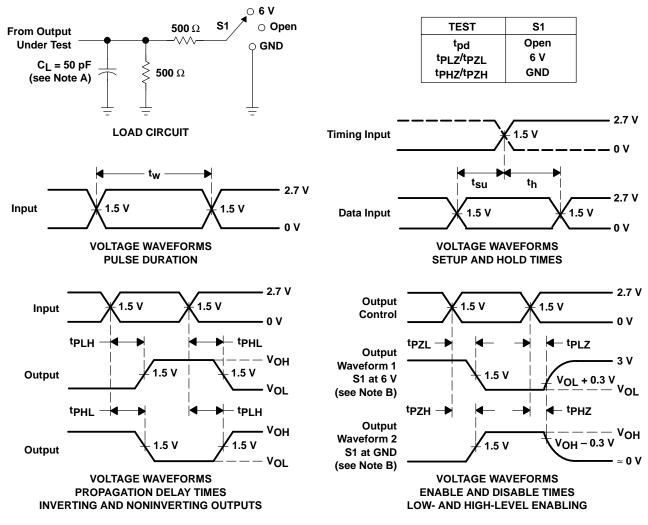
## switching characteristics over recommended operating free-air temperature range, C<sub>L</sub> = 50 pF (unless otherwise noted) (see Figure 1)

				SN54LVTH16240			SN74LVTH16240																		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 3.3 V ± 0.3 V								V <sub>CC</sub> = 2.7 V						$ \begin{array}{c c} 3.3 \ V \\ 3 \ V \\ V \\ C \\$		V <sub>CC</sub> = 3.3 V ± 0.3 V		= 2.7 V V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	MIN	түр†	MAX	MIN	MAX														
<sup>t</sup> PLH	А	Y	1	3.6	N	4.1	1	2.2	3.5		4	ns													
<sup>t</sup> PHL	A	I	1	3.6	NE.	4.1	1	2.7	3.5		4	115													
<sup>t</sup> PZH	OE	Y	1	4.2	RE	5.1	1	2.6	4		4.9	ns													
<sup>t</sup> PZL	ÛE	I	1.1	4.6	4	4.8	1.2	2.6	4.4		4.6	115													
<sup>t</sup> PHZ	OE	Y	1.9	4.5		5.2	2	3.4	4.5		5	ns													
<sup>t</sup> PLZ		I.	1.9	4.4		4.5	2	3.2	4.2		4.2	115													
t <sub>sk(o)</sub> ‡				2					0.5		0.5	ns													

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C. <sup>‡</sup> Skew between any two outputs of the same package switching in the same direction. This parameter is warranted but not production tested.



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## PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

#### Figure 1. Load Circuit and Voltage Waveforms



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